

## N-channel 650 V, 0.090 $\Omega$ typ., 22.5 A MDmesh™ M5 Power MOSFET in a PowerFLAT™ 8x8 HV package

Datasheet - production data

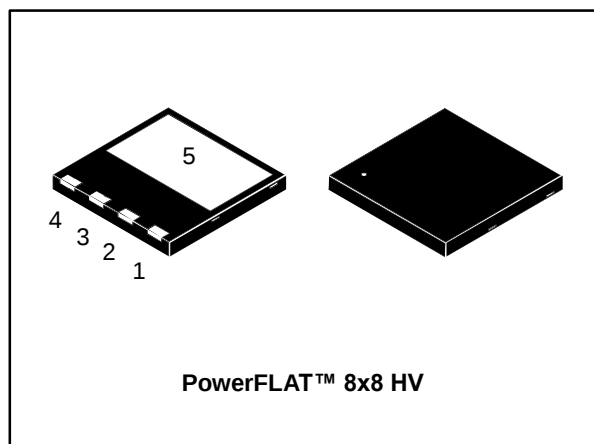
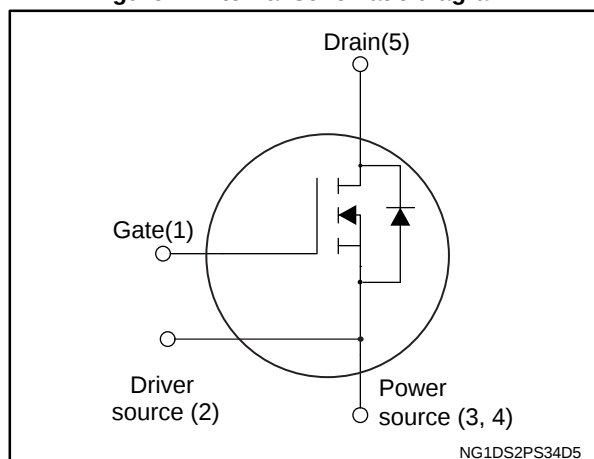


Figure 1: Internal schematic diagram



### Features

| Order code | V <sub>DS</sub> @ T <sub>Jmax</sub> | R <sub>DS(on)</sub> max. | I <sub>D</sub> |
|------------|-------------------------------------|--------------------------|----------------|
| STL38N65M5 | 710 V                               | 0.105 $\Omega$           | 22.5 A         |

- Extremely low R<sub>DS(on)</sub>
- Low gate charge and input capacitance
- Excellent switching performance
- 100% avalanche tested

### Applications

- Switching applications

### Description

This device is an N-channel Power MOSFET based on the MDmesh™ M5 innovative vertical process technology combined with the well-known PowerMESH™ horizontal layout. The resulting product offers extremely low on-resistance, making it particularly suitable for applications requiring high power and superior efficiency.

Table 1: Device summary

| Order code | Marking | Package           | Packaging     |
|------------|---------|-------------------|---------------|
| STL38N65M5 | 38N65M5 | PowerFLAT™ 8x8 HV | Tape and reel |

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## Contents

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# 1 Electrical ratings

Table 2: Absolute maximum ratings

| Symbol            | Parameter                                                                                                            | Value       | Unit             |
|-------------------|----------------------------------------------------------------------------------------------------------------------|-------------|------------------|
| $V_{DS}$          | Drain-source voltage                                                                                                 | 650         | V                |
| $V_{GS}$          | Gate-source voltage                                                                                                  | $\pm 25$    | V                |
| $I_D^{(1)}$       | Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$                                                       | 22.5        | A                |
| $I_D^{(1)}$       | Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$                                                      | 16          | A                |
| $I_{DM}^{(1)(2)}$ | Drain current (pulsed)                                                                                               | 90          | A                |
| $I_D^{(3)}$       | Drain current (continuous) at $T_{pcb} = 25\text{ }^\circ\text{C}$                                                   | 3.5         | A                |
| $I_D^{(3)}$       | Drain current (continuous) at $T_{pcb} = 100\text{ }^\circ\text{C}$                                                  | 2.2         | A                |
| $P_{TOT}^{(3)}$   | Total dissipation at $T_{pcb} = 25\text{ }^\circ\text{C}$                                                            | 2.8         | W                |
| $P_{TOT}^{(4)}$   | Total dissipation at $T_C = 25\text{ }^\circ\text{C}$                                                                | 150         | W                |
| $I_{AR}$          | Avalanche current, repetitive or notrepetitive (pulse width limited by $T_j$ max)                                    | 7           | A                |
| $E_{AS}$          | Single pulse avalanche energy (starting $T_j = 25\text{ }^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ ) | 660         | mJ               |
| $dv/dt^{(4)}$     | Peak diode recovery voltage slope                                                                                    | 15          | V/ns             |
| $T_{stg}$         | Storage temperature                                                                                                  | - 55 to 150 | $^\circ\text{C}$ |
| $T_j$             | Max. operating junction temperature                                                                                  | 150         |                  |

**Notes:**

<sup>(1)</sup>The value is rated according to  $R_{thj\text{-case}}$ .

<sup>(2)</sup>Pulse width limited by safe operating area.

<sup>(3)</sup>When mounted on FR-4 board of 1 inch<sup>2</sup>, 2oz Cu.

<sup>(4)</sup> $I_{SD} \leq 22.5\text{ A}$ ,  $di/dt \leq 400\text{ A}/\mu\text{s}$ ;  $V_{DS(\text{peak})} < V_{(BR)DSS}$ ,  $V_{DD} = 400\text{ V}$ .

Table 3: Thermal data

| Symbol                     | Parameter                            | Value | Unit                      |
|----------------------------|--------------------------------------|-------|---------------------------|
| $R_{thj\text{-case}}$      | Thermal resistance junction-case max | 0.83  | $^\circ\text{C}/\text{W}$ |
| $R_{thj\text{-pcb}}^{(1)}$ | Thermal resistance junction-pcb max  | 45    | $^\circ\text{C}/\text{W}$ |

**Notes:**

<sup>(1)</sup>When mounted on FR-4 board of 1 inch<sup>2</sup>, 2oz Cu.

## 2 Electrical characteristics

$T_C = 25\text{ }^{\circ}\text{C}$  unless otherwise specified

Table 4: On/off states

| Symbol        | Parameter                         | Test conditions                                                                          | Min. | Typ.  | Max.      | Unit          |
|---------------|-----------------------------------|------------------------------------------------------------------------------------------|------|-------|-----------|---------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage    | $V_{GS} = 0\text{ V}$ , $I_D = 1\text{ mA}$                                              | 650  |       |           | V             |
| $I_{DSS}$     | Zero gate voltage Drain current   | $V_{GS} = 0\text{ V}$ , $V_{DS} = 650\text{ V}$                                          |      |       | 1         | $\mu\text{A}$ |
|               |                                   | $V_{GS} = 0\text{ V}$ , $V_{DS} = 650\text{ V}$ ,<br>$T_C = 125\text{ }^{\circ}\text{C}$ |      |       | 100       | $\mu\text{A}$ |
| $I_{GSS}$     | Gate-body leakage current         | $V_{DS} = 0\text{ V}$ , $V_{GS} = \pm 25\text{ V}$                                       |      |       | $\pm 100$ | nA            |
| $V_{GS(th)}$  | Gate threshold voltage            | $V_{DS} = V_{GS}$ , $I_D = 250\text{ }\mu\text{A}$                                       | 3    | 4     | 5         | V             |
| $R_{DS(on)}$  | Static drain-source on-resistance | $V_{GS} = 10\text{ V}$ , $I_D = 12.5\text{ A}$                                           |      | 0.090 | 0.105     | $\Omega$      |

Table 5: Dynamic

| Symbol            | Parameter                                    | Test conditions                                                                                                                           | Min. | Typ. | Max. | Unit     |
|-------------------|----------------------------------------------|-------------------------------------------------------------------------------------------------------------------------------------------|------|------|------|----------|
| $C_{iss}$         | Input capacitance                            | $V_{DS} = 100\text{ V}$ , $f = 1\text{ MHz}$ ,<br>$V_{GS} = 0\text{ V}$                                                                   | -    | 3000 | -    | pF       |
| $C_{oss}$         | Output capacitance                           |                                                                                                                                           | -    | 74   | -    | pF       |
| $C_{rss}$         | Reverse transfer capacitance                 |                                                                                                                                           | -    | 5.8  | -    | pF       |
| $C_{o(er)}^{(1)}$ | Equivalent output capacitance energy related | $V_{DS} = 0\text{ to }80\% V_{(BR)DSS}$ ,<br>$V_{GS} = 0\text{ V}$                                                                        | -    | 70   | -    | pF       |
| $C_{o(tr)}^{(2)}$ | Equivalent output capacitance time related   |                                                                                                                                           | -    | 244  | -    | pF       |
| $R_G$             | Intrinsic gate resistance                    | $f = 1\text{ MHz}$                                                                                                                        | -    | 2.4  | -    | $\Omega$ |
| $Q_g$             | Total gate charge                            | $V_{DD} = 520\text{ V}$ , $I_D = 15\text{ A}$ ,<br>$V_{GS} = 10\text{ V}$ (see <a href="#">Figure 16</a> :<br>"Gate charge test circuit") | -    | 71   | -    | nC       |
| $Q_{gs}$          | Gate-source charge                           |                                                                                                                                           | -    | 18   | -    | nC       |
| $Q_{gd}$          | Gate-drain charge                            |                                                                                                                                           | -    | 30   | -    | nC       |

**Notes:**

<sup>(1)</sup> $C_{o(er)}$  is defined as a constant equivalent capacitance giving the same stored energy as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

<sup>(2)</sup> $C_{o(tr)}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

Table 6: Switching times

| Symbol       | Parameter          | Test conditions                                                                                                                                                                                                                                                   | Min. | Typ. | Max. | Unit |
|--------------|--------------------|-------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|------|------|------|------|
| $t_{d(V)}$   | Voltage delay time | $V_{DD} = 400\text{ V}$ , $I_D = 20\text{ A}$<br>$R_G = 4.7\ \Omega$ , $V_{GS} = 10\text{ V}$<br>(see <a href="#">Figure 17</a> : "Test circuit for inductive load switching and diode recovery times" and <a href="#">Figure 20</a> : "Switching time waveform") | -    | 66   | -    | ns   |
| $t_{r(V)}$   | Voltage rise time  |                                                                                                                                                                                                                                                                   | -    | 9    | -    | ns   |
| $t_{f(i)}$   | Crossing fall time |                                                                                                                                                                                                                                                                   | -    | 9    | -    | ns   |
| $t_{c(off)}$ | Crossing time      |                                                                                                                                                                                                                                                                   | -    | 13   | -    | ns   |

Table 7: Source drain diode

| Symbol              | Parameter                     | Test conditions                                                                                                                                                                                                                          | Min. | Typ. | Max. | Unit          |
|---------------------|-------------------------------|------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|------|------|------|---------------|
| $I_{SD}^{(1)}$      | Source-drain current          |                                                                                                                                                                                                                                          | -    |      | 22.5 | A             |
| $I_{SDM}^{(1),(2)}$ | Source-drain current (pulsed) |                                                                                                                                                                                                                                          | -    |      | 90   | A             |
| $V_{SD}^{(3)}$      | Forward on voltage            | $V_{GS} = 0\text{ V}$ , $I_{SD} = 22.5\text{ A}$                                                                                                                                                                                         | -    |      | 1.5  | V             |
| $t_{rr}$            | Reverse recovery time         | $I_{SD} = 22.5\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ ,<br>$V_{DD} = 100\text{ V}$ (see <a href="#">Figure 17</a> : "Test circuit for inductive load switching and diode recovery times")                                        | -    | 354  |      | ns            |
| $Q_{rr}$            | Reverse recovery charge       |                                                                                                                                                                                                                                          | -    | 6    |      | $\mu\text{C}$ |
| $I_{RRM}$           | Reverse recovery current      |                                                                                                                                                                                                                                          | -    | 34   |      | A             |
| $t_{rr}$            | Reverse recovery time         | $I_{SD} = 22.5\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ ,<br>$V_{DD} = 100\text{ V}$ , $T_J = 150\text{ }^\circ\text{C}$<br>(see <a href="#">Figure 17</a> : "Test circuit for inductive load switching and diode recovery times") | -    | 428  |      | ns            |
| $Q_{rr}$            | Reverse recovery charge       |                                                                                                                                                                                                                                          | -    | 8    |      | $\mu\text{C}$ |
| $I_{RRM}$           | Reverse recovery current      |                                                                                                                                                                                                                                          | -    | 38   |      | A             |

**Notes:**

<sup>(1)</sup>The value is rated according to  $R_{thj-case}$  and limited by package.

<sup>(2)</sup>Pulse width is limited by safe operating area

<sup>(3)</sup>Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

## 2.1 Electrical characteristics (curves)

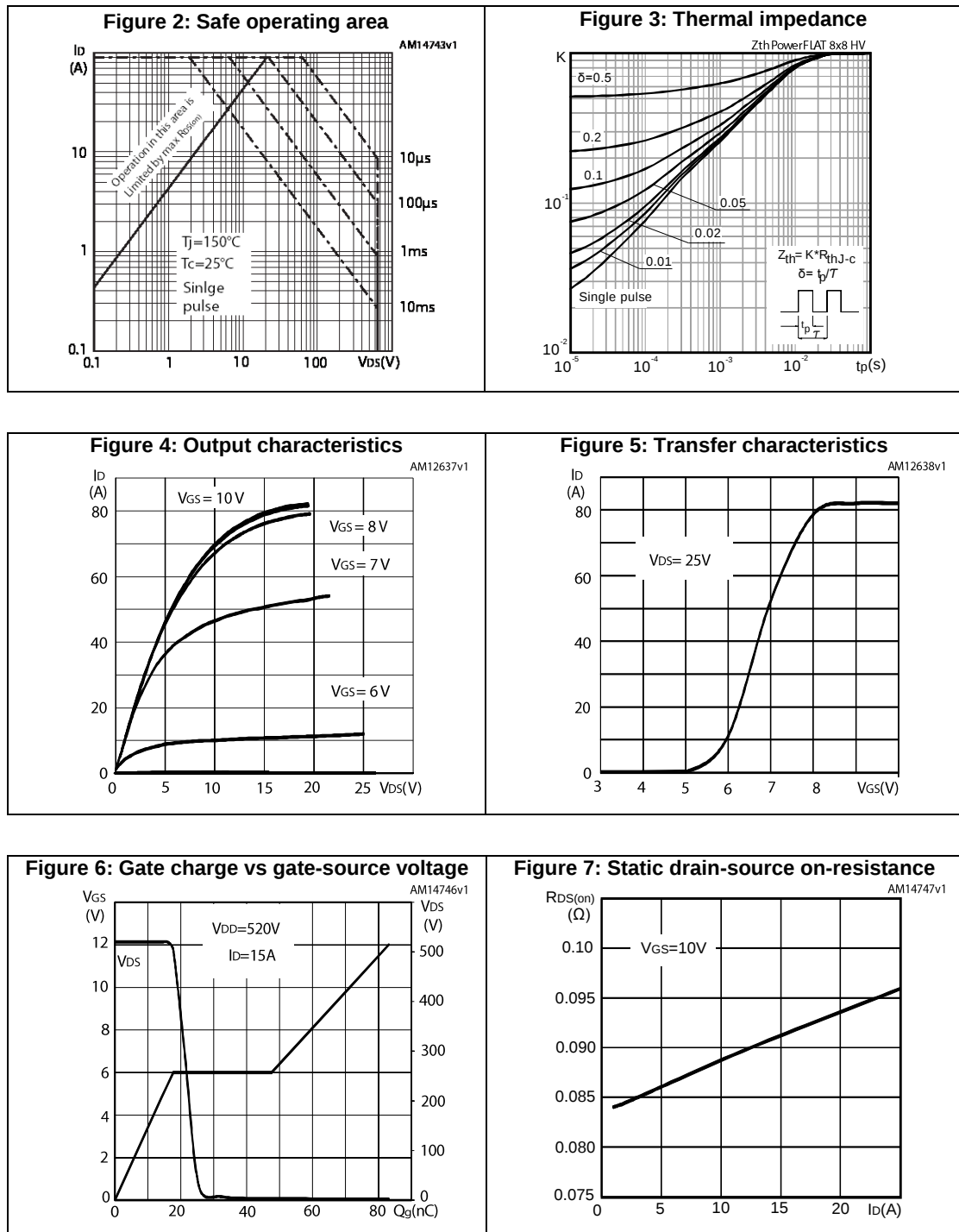


Figure 8: Capacitance variations

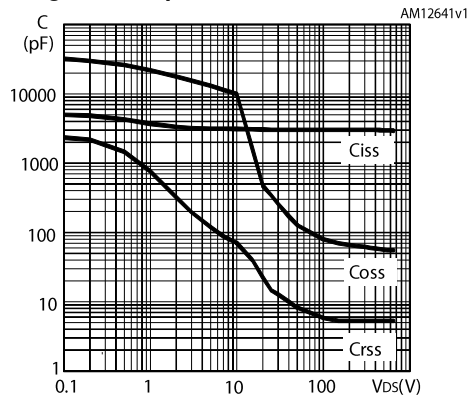


Figure 9: Normalized gate threshold voltage vs temperature

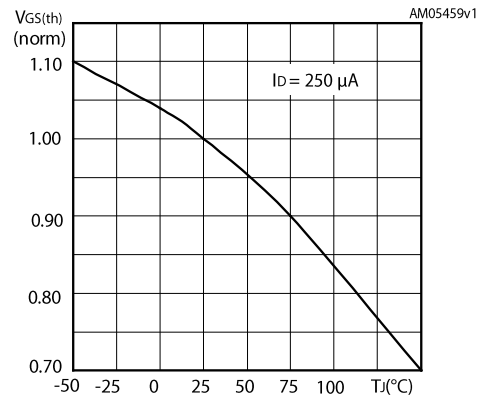


Figure 10: Normalized on-resistance vs temperature

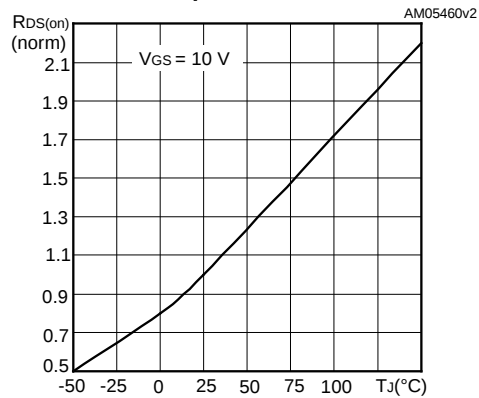


Figure 11: Normalized V(BR)DSS vs temperature

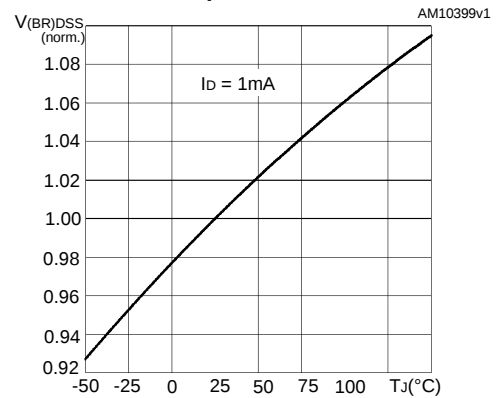


Figure 12: Output capacitance stored energy

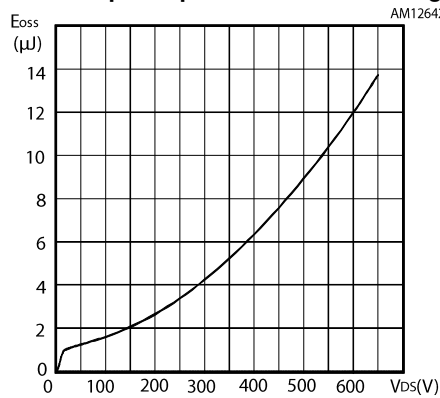


Figure 13: Source-drain diode forward characteristics

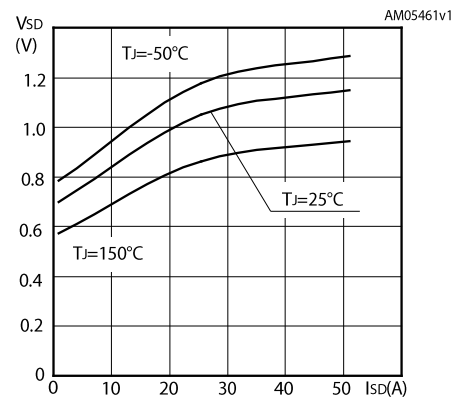
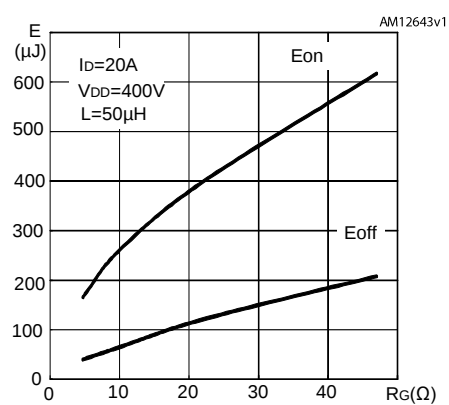


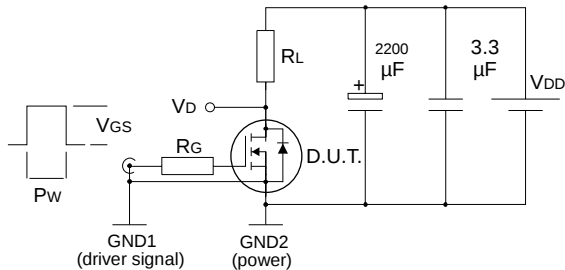
Figure 14: Switching losses vs gate resistance



The previous figure  $E_{on}$  includes reverse recovery of a SiC diode.

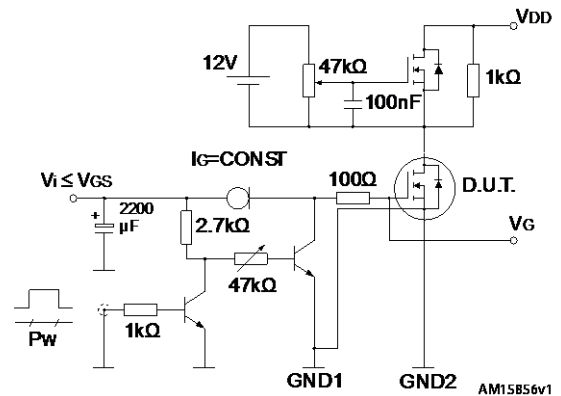
### 3 Test circuits

Figure 15: Switching times test circuit for resistive load



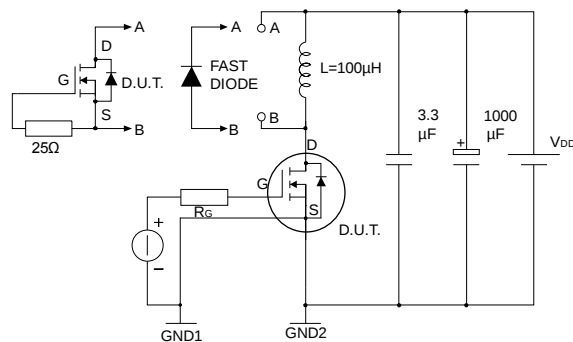
AM15855v1

Figure 16: Gate charge test circuit



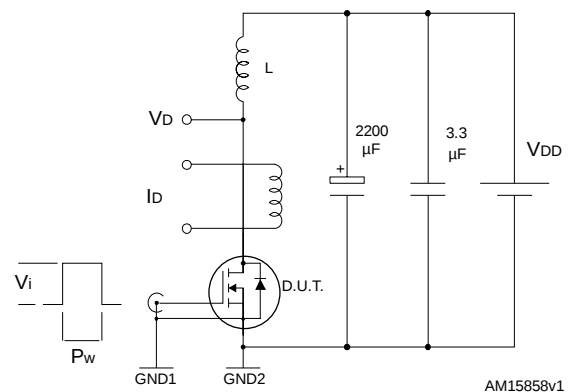
AM15856v1

Figure 17: Test circuit for inductive load switching and diode recovery times



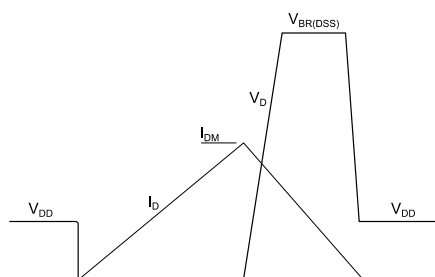
AM15857v1

Figure 18: Unclamped inductive load test circuit



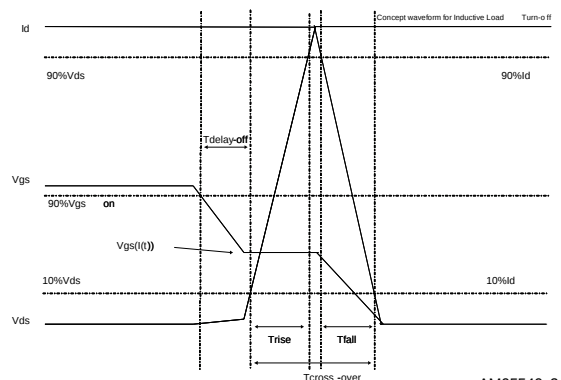
AM15858v1

Figure 19: Unclamped inductive waveform



AM01472v1

Figure 20: Switching time waveform



AM05540v2

## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **[www.st.com](http://www.st.com)**. ECOPACK® is an ST trademark.

## 4.1 PowerFLAT™ 8x8 HV package information

Figure 21: PowerFLAT™ 8x8 HV drawing

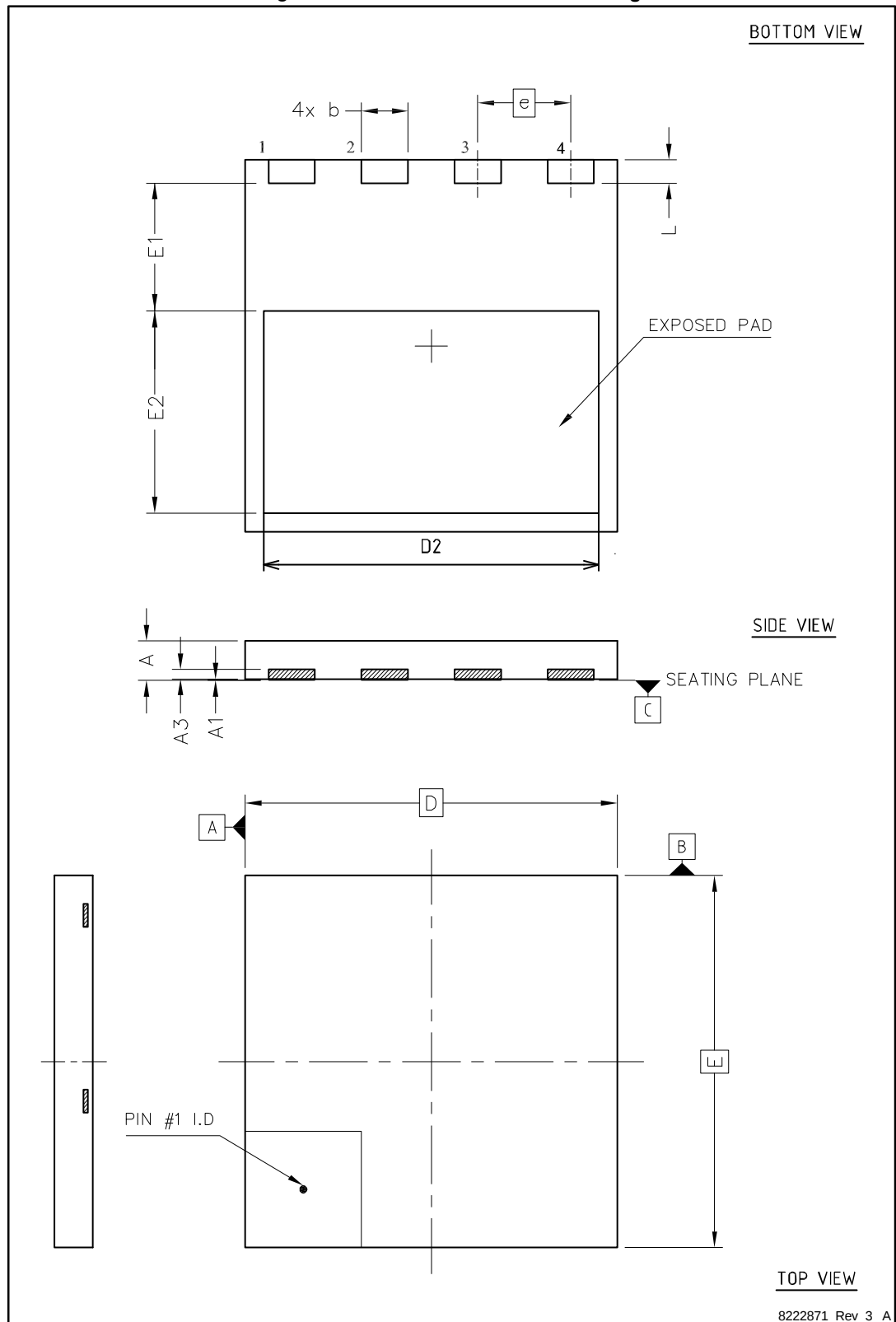
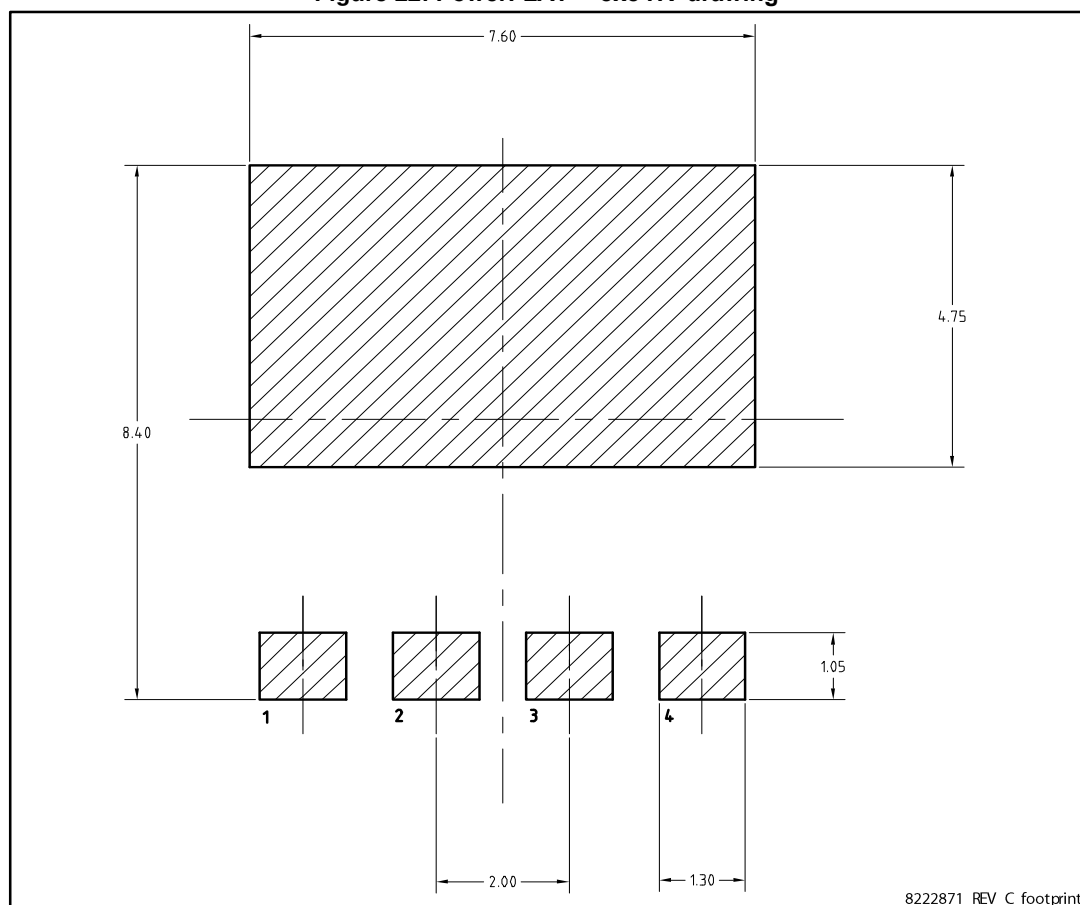


Table 8: PowerFLAT™ 8x8 HV mechanical data

| Dim. | mm   |      |      |
|------|------|------|------|
|      | Min. | Typ. | Max. |
| A    | 0.75 | 0.85 | 0.95 |
| A1   | 0.00 |      | 0.05 |
| A3   | 0.10 | 0.20 | 0.30 |
| b    | 0.90 | 1.00 | 1.10 |
| D    | 7.90 | 8.00 | 8.10 |
| E    | 7.90 | 8.00 | 8.10 |
| D2   | 7.10 | 7.20 | 7.30 |
| E1   | 2.65 | 2.75 | 2.85 |
| E2   | 4.25 | 4.35 | 4.45 |
| e    |      | 2.00 |      |
| L    | 0.40 | 0.50 | 0.60 |

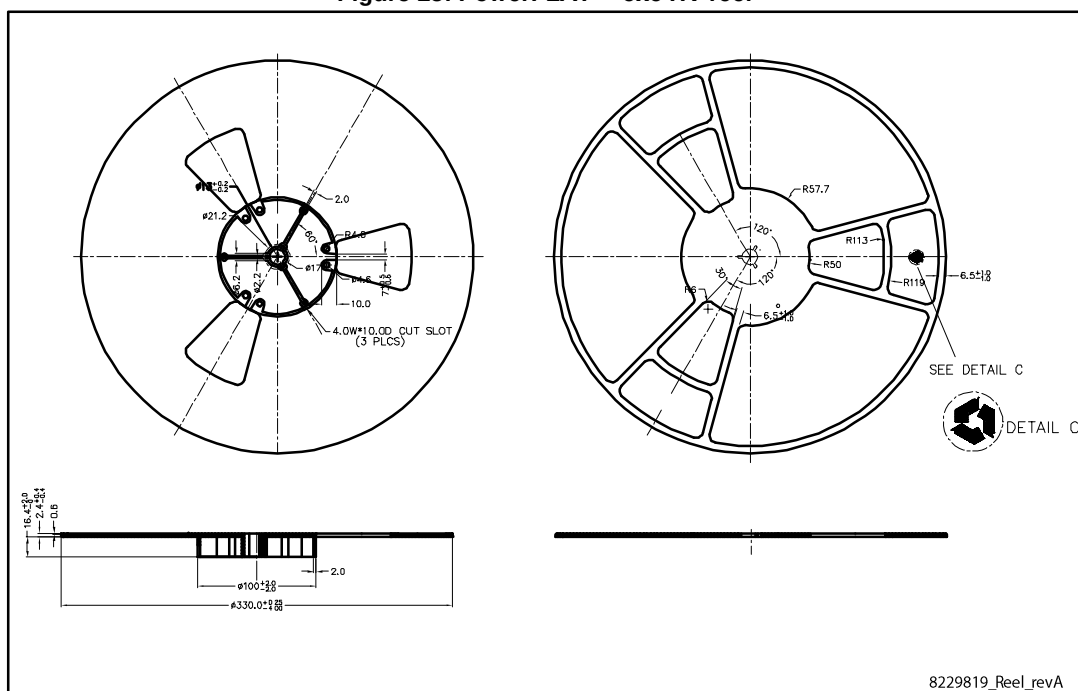
Figure 22: PowerFLAT™ 8x8 HV drawing



All the dimensions are in millimeters.



Figure 25: PowerFLAT™ 8x8 HV reel



## 5 Revision history

**Table 9: Document revision history**

| Date        | Revision | Changes                                                                                                                                                                                            |
|-------------|----------|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| 17-Jan-2013 | 1        | First release.                                                                                                                                                                                     |
| 27-Aug-2015 | 2        | Updated title, features, internal schematic and description on cover page.<br>Document status promoted from preliminary to production data.<br>Updated package information.<br>Minor text changes. |

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